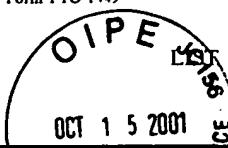


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1670	SERIAL NO. 09/881,407	
LIST OF ARTS SEARCHED BY APPLICANT (Use several sheets if necessary)			APPLICANT Zhongze Wang				
			FILING DATE June 13, 2001		GROUP 2811		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
PEP	AA	5,254,489	10/19/93	Nakata			
PEP	AB	5,464,792	11/07/95	Tseng et al.			
PEP	AC	5,596,218	01/21/97	Soleimani et al.			
PEP	AD	5,620,908	04/15/97	Inoh et al.			
PEP	AE	5,674,788	10/07/97	Wristers et al.			
PEP	AF	5,716,864	02/10/98	Abe			
PEP	AG	5,960,302	09/28/99	Ma et al.			
PEP	AH	5,972,783	10/26/99	Arai et al.			
PEP	AI	5,994,749	11/30/99	Oda			
PEP	AJ	6,225,151	05/01/01	Gardner et al.			
PEP	AK	4,651,406	03/24/87	Shimizu et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
PEP	AL	WO 96/39713	12/12/96	PCT			No
PEP	AM	JP06302813A	04/09/93	Japan (Citizen Watch Co. Ltd.)			
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
PEP	AR		Doyle et al., "Simultaneous Growth of Different Thickness Gate Oxides in Silicon CMOS Processing", IEEE Electron Device Letters, Vol. 16, No. 7.				
PEP	AS		Ko et al., "The Effect of Nitrogen Incorporation Into the Gate Oxide by Using Shallow Implantation of Nitrogen and Drive-in Process", 1998 IEEE, 0-7803-4932-6/98.				
	AT		Kurni et al., "The Effects of Nitrogen Implantation into P + Poly-Silicon Gate on Gate Oxide Properties", 1994 Symposium on VLSI Technology Digest of Technical Papers, pp. 107-108.				
EXAMINER <i>Paula E. Rabis</i>			DATE CONSIDERED <i>17 Sept. 2002</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449  LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) OCT 15 2001				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1670		SERIAL NO. 09/881,407	
				APPLICANT Zhongze Wang					
				FILING DATE June 13, 2001		GROUP 2811			
U.S. PATENT DOCUMENTS									
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate			
RP	AA 5,502,009	03/26/96	Lin						
RP	AB 6,136,654	10/24/00	Kraft et al.						
RP	AC 6,165,846	12/26/00	Carns et al.						
RP	AD 6,200,834-B1	03/13/01	Bronner et al.						
RP	AE 6,093,661	07/25/00	Trivedi et al.						
	AF								
	AG								
	AH								
	AI								
	AJ								
	AK								
FOREIGN PATENT DOCUMENTS									
	Document Number	Date	Country	Class	Subclass	Translation			
						Yes No			
	AL								
	AM								
	AN								
	AO								
	AP								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
RP	AR		C.T. Liu et al.; "Multiple Gate Oxide Thickness for 2GHz System-on-a-Chip Technologies"; IEEE 1998; pp. 21.2.1-21.2.4						
	AS								
	AT								
EXAMINER				DATE CONSIDERED					17 Sept. 2002
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1670SERIAL NO.
09/881,407LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Zhongze WangFILING DATE
June 13, 2001GROUP
2811

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
PEP	AA	5,763,922	06/09/98	Chau			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

RECEIVED
JUL 17 2002
TECHNOLOGY CENTER 2800

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
PEP	AM	326352	11/01	Japan				
	AN							
	AO							
	AP							
	AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER *Paula E. Rabin*

DATE CONSIDERED 17 Sept. 2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.